## NB100LVEP91

### 2.5 V/3.3 V Any Level Positive Input to -2.5 V/-3.3 V LVNECL Output Translator

## Description

The NB100LVEP91 is a triple any level positive input to NECL output translator. The device accepts LVPECL, LVTTL, LVCMOS, HSTL, CML or LVDS signals, and translates them to differential LVNECL output signals ( $-2.5 \mathrm{~V} /-3.3 \mathrm{~V}$ ).

To accomplish the level translation the LVEP91 requires three power rails. The $\mathrm{V}_{\mathrm{CC}}$ pins should be connected to the positive power supply, and the $\mathrm{V}_{\mathrm{EE}}$ pin should be connected to the negative power supply. The GND pins are connected to the system ground plane. Both $\mathrm{V}_{\mathrm{EE}}$ and $\mathrm{V}_{\mathrm{CC}}$ should be bypassed to ground via $0.01 \mu \mathrm{~F}$ capacitors.

Under open input conditions, the $\overline{\mathrm{D}}$ input will be biased at $\mathrm{V}_{\mathrm{CC}} / 2$ and the D input will be pulled to GND. These conditions will force the Q outputs to a low state, and Q outputs to a high state, which will ensure stability.

The $\mathrm{V}_{\mathrm{BB}}$ pin, an internally generated voltage supply, is available to this device only. For single-ended input conditions, the unused differential input is connected to $\mathrm{V}_{\mathrm{BB}}$ as a switching reference voltage. $\mathrm{V}_{\mathrm{BB}}$ may also rebias AC coupled inputs. When used, decouple $\mathrm{V}_{\mathrm{BB}}$ and $\mathrm{V}_{\mathrm{CC}}$ via a $0.01 \mu \mathrm{~F}$ capacitor and limit current sourcing or sinking to 0.5 mA . When not used, $\mathrm{V}_{\mathrm{BB}}$ should be left open.

## Features

- Maximum Input Clock Frequency $>2.0 \mathrm{GHz}$ Typical
- Maximum Input Data Rate $>2.0 \mathrm{~Gb} / \mathrm{s}$ Typical
- 500 ps Typical Propagation Delay
- Operating Range: $\mathrm{V}_{\mathrm{CC}}=2.375 \mathrm{~V}$ to 3.8 V ;
$\mathrm{V}_{\mathrm{EE}}=-2.375 \mathrm{~V}$ to $-3.8 \mathrm{~V} ; \mathrm{GND}=0 \mathrm{~V}$
- Q Output will Default LOW with Inputs Open or at GND
- $\mathrm{Pb}-$ Free Packages are Available*


## ON Semiconductor ${ }^{\circledR}$

http://onsemi.com


| A | $=$ Assembly Location |
| :--- | :--- |
| WL, L | $=$ Wafer Lot |
| YY, Y | $=$ Year |
| WW, W | $=$ Work Week |
| Gor | $=$ Pb-Free Package |

(Note: Microdot may be in either location)
*For additional marking information, refer to Application Note AND8002/D.

## ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 8 of this data sheet.

[^0]
## NB100LVEP91



Figure 1. Logic Diagram

Table 1. PIN DESCRIPTION

| Pin |  | Name | 1/0 | Default State | Description |
| :---: | :---: | :---: | :---: | :---: | :---: |
| SOIC | QFN |  |  |  |  |
| 1,20 | 3, 4, 12 | $\mathrm{V}_{\mathrm{CC}}$ | - | - | Positive Supply Voltage. All $\mathrm{V}_{\mathrm{CC}}$ Pins must be Externally Connected to Power Supply to Guarantee Proper Operation. |
| 10 | 15, 16 | $\mathrm{V}_{\mathrm{EE}}$ | - | - | Negative Supply Voltage. All $\mathrm{V}_{\text {EE }}$ Pins must be Externally Connected to Power Supply to Guarantee Proper Operation. |
| 14, 17 | $\begin{gathered} 19,20,23, \\ 24 \end{gathered}$ | GND | - | - | Ground. |
| 4, 7 | 7, 11 | $\mathrm{V}_{\mathrm{BB}}$ | - | - | ECL Reference Voltage Output |
| 2, 5, 8 | 5, 8, 13 | D[0:2] | LVPECL, LVDS, LVTTL, LVCMOS, CML, HSTL Input | Low | Noninverted Differential Inputs [0:2]. Internal $75 \mathrm{k} \Omega$ to $\mathrm{V}_{\mathrm{EE}}$. |
| 3, 6, 9 | 6, 9, 14 | $\overline{\mathrm{D}[0: 2]}$ | LVPECL, LVDS, LVTTL,LVCMOS, CML, HSTL Input | High | Inverted Differential Inputs [0:2]. Internal $75 \mathrm{k} \Omega$ to $\mathrm{V}_{\mathrm{EE}}$ and $75 \mathrm{k} \Omega$ to $\mathrm{V}_{\mathrm{cc}}$. When Inputs are Left Open They Default to $\left(V_{C C}-V_{E E}\right) / 2$. |
| 19,16,13 | 2, 18, 22 | Q[0:2] | LVNECL Output | - | Noninverted Differential Outputs [0:2]. Typically Terminated with $50 \Omega$ to $\mathrm{V}_{\mathrm{TT}}=\mathrm{V}_{\mathrm{CC}}-2 \mathrm{~V}$ |
| 18,15,12 | 1,21, 17 | Q[0:2] | LVNECL Output | - | Inverted Differential Outputs [0:2]. Typically Terminated with $50 \Omega$ to $\mathrm{V}_{\mathrm{TT}}=\mathrm{V}_{\mathrm{CC}}-2 \mathrm{~V}$ |
| 11 | 10 | NC | - | - | No Connect. The NC Pin is NOT Electrically Connected to the Die and may Safely be Connected to Any Voltage from $V_{E E}$ to $V_{C C}$. |
| N/A | - | EP | - |  | Exposed Pad. (Note 1) |

1. The thermally conductive exposed pad on the package bottom (see case drawing) must be attached to a heat-sinking conduit.

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Figure 2. SOIC-20 Lead Pinout (Top View)
*AII $\mathrm{V}_{\mathrm{CC}}, \mathrm{V}_{\mathrm{EE}}$ and GND pins must be externally connected to a power supply and the underside exposed pad must be attached to an adequate heat-sinking conduit to guarantee proper operation.

Table 2. ATTRIBUTES

| Characteristics |  | Value |  |
| :---: | :---: | :---: | :---: |
| Internal Input Pulldown Resistor | (R1) | $75 \mathrm{k} \Omega$ |  |
| Internal Input Pullup Resistor | (R2) | $75 \mathrm{k} \Omega$ |  |
| ESD Protection | Human Body Model Machine Model Charged Device Model | $\begin{gathered} >2 \mathrm{kV} \\ >150 \mathrm{~V} \\ >2 \mathrm{kV} \end{gathered}$ |  |
| Moisture Sensitivity (Note 2) |  | Pb Pkg | Pb-Free Pkg |
| $\begin{array}{r} \text { SO-20 WB } \\ \text { QFN-24 } \end{array}$ |  | Level 1 Level 1 | Level 3 Level 1 |
| Flammability Rating | Oxygen Index: 28 to 34 | UL 94 V-0 @ 0.125 in |  |
| Transistor Count |  | 446 Devices |  |
| Meets or exceeds JEDEC Spec EIA/JESD78 IC Latchup Test |  |  |  |

2. For additional information, see Application Note AND8003/D.

Table 3. MAXIMUM RATINGS

| Symbol | Parameter | Condition 1 | Condition 2 | Rating | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {CC }}$ | Positive Power Supply | GND $=0 \mathrm{~V}$ |  | 3.8 to 0 | V |
| $\mathrm{V}_{\text {EE }}$ | Negative Power Supply | GND $=0 \mathrm{~V}$ |  | -3.8 to 0 | V |
| $V_{1}$ | Positive Input Voltage | GND $=0 \mathrm{~V}$ | $\mathrm{V}_{\mathrm{I}} \leq \mathrm{V}_{\mathrm{CC}}$ | 3.8 to 0 | V |
| $\mathrm{V}_{\text {OP }}$ | Operating Voltage | GND $=0 \mathrm{~V}$ | $\mathrm{V}_{\mathrm{CC}}-\mathrm{V}_{\mathrm{EE}}$ | 7.6 to 0 | V |
| $\mathrm{I}_{\text {out }}$ | Output Current | Continuous Surge |  | $\begin{gathered} 50 \\ 100 \end{gathered}$ | $\begin{aligned} & \mathrm{mA} \\ & \mathrm{~mA} \end{aligned}$ |
| $\mathrm{I}_{\mathrm{BB}}$ | PECL V ${ }_{\text {BB }}$ Sink/Source |  |  | $\pm 0.5$ | mA |
| $\mathrm{T}_{\text {A }}$ | Operating Temperature Range |  |  | -40 to +85 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\text {stg }}$ | Storage Temperature Range |  |  | -65 to +150 | ${ }^{\circ} \mathrm{C}$ |
| $\theta_{\mathrm{JA}}$ | Thermal Resistance (Junction-to-Ambient) JESD 51-3 (1S-Single Layer Test Board) | $\begin{aligned} & 0 \text { lfpm } \\ & 500 \mathrm{lfpm} \end{aligned}$ | $\begin{aligned} & \hline \text { SOIC-20 } \\ & \text { SOIC-20 } \end{aligned}$ | $\begin{aligned} & 90 \\ & 60 \end{aligned}$ | $\begin{array}{\|l\|} \hline{ }^{\circ} \mathrm{C} / \mathrm{W} \\ { }^{\circ} \mathrm{C} / \mathrm{W} \end{array}$ |
| $\theta_{\text {JA }}$ | Thermal Resistance (Junction-to-Ambient) JESD 51-6 (2S2P Multilayer Test Board) with Filled Thermal Vias | $\begin{aligned} & 0 \text { Ifpm } \\ & 500 \mathrm{lfpm} \end{aligned}$ | $\begin{aligned} & \text { QFN-24 } \\ & \text { QFN-24 } \end{aligned}$ | $\begin{aligned} & 37 \\ & 32 \end{aligned}$ | $\begin{aligned} & \hline{ }^{\circ} \mathrm{C} / \mathrm{W} \\ & { }^{\circ} \mathrm{C} / \mathrm{W} \end{aligned}$ |
| $\theta_{\text {Jc }}$ | Thermal Resistance (Junction-to-Case) | Standard Board | $\begin{aligned} & \hline \text { SOIC-20 } \\ & \text { QFN-24 } \end{aligned}$ | $\begin{aligned} & 30 \text { to } 35 \\ & 11 \end{aligned}$ | $\begin{array}{\|l\|} \hline{ }^{\circ} \mathrm{C} / \mathrm{W} \\ { }^{\circ} \mathrm{C} / \mathrm{W} \end{array}$ |
| $\mathrm{T}_{\text {sol }}$ | Wave SolderPb <br> $\mathrm{Pb}-$ Free |  |  | $\begin{aligned} & 225 \\ & 225 \end{aligned}$ | ${ }^{\circ} \mathrm{C}$ |

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

Table 4. DC CHARACTERISTICS POSITIVE INPUTS $\mathrm{V}_{\mathrm{CC}}=2.5 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}}=-2.375$ to -3.8 V , $\mathrm{GND}=0 \mathrm{~V}$ (Note 3)

| Symbol | Characteristic |  | -40 ${ }^{\circ}$ |  |  | $25^{\circ} \mathrm{C}$ |  |  | $85^{\circ} \mathrm{C}$ |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max |  |
| ICC | Positive Power Supply Current |  | 10 | 14 | 20 | 10 | 14 | 20 | 10 | 14 | 20 | mA |
| $\mathrm{V}_{\mathrm{IH}}$ | Input HIGH Voltage (Single-Ended) |  | 1335 |  | $\mathrm{V}_{\mathrm{CC}}$ | 1335 |  | $\mathrm{V}_{\mathrm{CC}}$ | 1335 |  | $\mathrm{V}_{\text {CC }}$ | mV |
| $\mathrm{V}_{\text {IL }}$ | Input LOW Voltage (Single-Ended) |  | GND |  | 875 | GND |  | 875 | GND |  | 875 | mV |
| $\mathrm{V}_{\text {IHCMR }}$ | Input HIGH Voltage Common Mode Range (Differential Configuration) (Note 4) |  | 0 |  | 2.5 | 0 |  | 2.5 | 0 |  | 2.5 | V |
| $\mathrm{I}_{\mathrm{IH}}$ | Input HIGH Current (@ $\mathrm{V}_{\mathrm{IH}}$ ) |  |  |  | 150 |  |  | 150 |  |  | 150 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {IL }}$ | Input LOW Current (@ V ${ }_{\text {IL }}$ ) | $\frac{\mathrm{D}}{\mathrm{D}}$ | $\begin{gathered} \hline 0.5 \\ -150 \end{gathered}$ |  |  | $\begin{gathered} \hline 0.5 \\ -150 \end{gathered}$ |  |  | $\begin{gathered} \hline 0.5 \\ -150 \end{gathered}$ |  |  | $\mu \mathrm{A}$ |

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm . Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.
3. Input parameters vary $1: 1$ with $\mathrm{V}_{\mathrm{CC}} . \mathrm{V}_{\mathrm{CC}}$ can vary $+1.3 \mathrm{~V} /-0.125 \mathrm{~V}$.
4. $\mathrm{V}_{\text {IHCMR }}$ min varies $1: 1$ with $G N D$. $\mathrm{V}_{\mathrm{IHCMR}}$ max varies $1: 1$ with $\mathrm{V}_{\mathrm{CC}}$.

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Table 5. DC CHARACTERISTICS POSITIVE INPUT $\mathrm{V}_{\mathrm{CC}}=3.3 \mathrm{~V}$; $\mathrm{V}_{\mathrm{EE}}=-2.375 \mathrm{~V}$ to -3.8 V ; GND $=0 \mathrm{~V}$ (Note 5)

| Symbol | Characteristic | $-40^{\circ} \mathrm{C}$ |  |  | $25^{\circ} \mathrm{C}$ |  |  | $85^{\circ} \mathrm{C}$ |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max |  |
| ICC | Positive Power Supply Current | 10 | 16 | 24 | 10 | 16 | 24 | 10 | 16 | 24 | mA |
| $\mathrm{V}_{\mathrm{IH}}$ | Input HIGH Voltage (Single-Ended) | 2135 |  | $\mathrm{V}_{\mathrm{CC}}$ | 2135 |  | $\mathrm{V}_{\mathrm{CC}}$ | 2135 |  | $\mathrm{V}_{\text {CC }}$ | mV |
| $\mathrm{V}_{\text {IL }}$ | Input LOW Voltage (Single-Ended) | GND |  | 1675 | GND |  | 1675 | GND |  | 1675 | mV |
| $\mathrm{V}_{\text {BB }}$ | PECL Output Voltage Reference | 1775 | 1875 | 1975 | 1775 | 1875 | 1975 | 1775 | 1875 | 1975 | mV |
| $\mathrm{V}_{\text {IHCMR }}$ | Input HIGH Voltage Common Mode Range (Differential Configuration) (Note 6) | 0 |  | 3.3 | 0 |  | 3.3 | 0 |  | 3.3 | V |
| $\mathrm{I}_{\mathrm{H}}$ | Input HIGH Current (@ V ${ }_{\text {IH }}$ ) |  |  | 150 |  |  | 150 |  |  | 150 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {IL }}$ | Input LOW Current ( V VIL) $\frac{\mathrm{D}}{\mathrm{D}}$ | $\begin{gathered} 0.5 \\ -150 \end{gathered}$ |  |  | $\begin{gathered} \hline 0.5 \\ -150 \end{gathered}$ |  |  | $\begin{gathered} \hline 0.5 \\ -150 \end{gathered}$ |  |  | $\mu \mathrm{A}$ |

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.
5. Input parameters vary $1: 1$ with $\mathrm{V}_{\mathrm{CC}} . \mathrm{V}_{\mathrm{CC}}$ can vary $+0.5 /-0.925 \mathrm{~V}$.
6. $\mathrm{V}_{\text {IHCMR }}$ min varies $1: 1$ with $G N D$. $\mathrm{V}_{\text {IHCMR }}$ max varies $1: 1$ with $\mathrm{V}_{\mathrm{CC}}$.

Table 6. DC CHARACTERISTICS NECL OUTPUT $\mathrm{V}_{\mathrm{CC}}=2.375 \mathrm{~V}$ to 3.8 V ; $\mathrm{V}_{\mathrm{EE}}=-2.375 \mathrm{~V}$ to -3.8 V ; $\mathrm{GND}=0 \mathrm{~V}$ (Note 7)

| Symbol | Characteristic | $-40^{\circ} \mathrm{C}$ |  |  | $25^{\circ} \mathrm{C}$ |  |  | $85^{\circ} \mathrm{C}$ |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max |  |
| $\mathrm{I}_{\text {EE }}$ | Negative Power Supply Current | 40 | 50 | 60 | 38 | 50 | 68 | 38 | 50 | 68 | mA |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage (Note 8) | -1145 | -1020 | -895 | -1145 | -1020 | -895 | -1145 | -1020 | -895 | mV |
| $\mathrm{V}_{\text {OL }}$ | Output LOW Voltage (Note 8) | -1945 | -1770 | -1600 | -1945 | -1770 | -1600 | -1945 | -1770 | -1600 | mV |

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm . Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.
7. Output parameters vary $1: 1$ with GND.
8. All loading with $50 \Omega$ resistor to GND -2.0 V .

Table 7. AC CHARACTERISTICS $\mathrm{V}_{\mathrm{CC}}=2.375 \mathrm{~V}$ to $3.8 \mathrm{~V} ; \mathrm{V}_{\mathrm{EE}}=-2.375 \mathrm{~V}$ to $-3.8 \mathrm{~V} ; \mathrm{GND}=0 \mathrm{~V}$

|  | Characteristic | $-40^{\circ} \mathrm{C}$ |  |  | $25^{\circ} \mathrm{C}$ |  |  | $85^{\circ} \mathrm{C}$ |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Symbol |  | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max |  |
| V OUTPP | Output Voltage Amplitude $f_{\text {in }} \leq 1.0 \mathrm{GHz}$ <br> (Figure 4) $f_{i n} \leq 1.5 \mathrm{GHz}$ <br> (Note 9) $f_{\text {in }} \leq 2.0 \mathrm{GHz}$ | $\begin{aligned} & 575 \\ & 525 \\ & 300 \end{aligned}$ | $\begin{aligned} & 800 \\ & 750 \\ & 600 \end{aligned}$ |  | $\begin{aligned} & 600 \\ & 525 \\ & 250 \end{aligned}$ | $\begin{aligned} & 800 \\ & 750 \\ & 550 \end{aligned}$ |  | $\begin{aligned} & 550 \\ & 400 \\ & 150 \end{aligned}$ | $\begin{aligned} & 800 \\ & 750 \\ & 50 \end{aligned}$ |  | mV |
| $\begin{aligned} & \mathrm{t}_{\text {PLH }} \\ & \mathrm{t}_{\text {PHLO }} \end{aligned}$ | Propagation Delay Differential <br> D to Q Single-Ended | $\begin{aligned} & 375 \\ & 300 \end{aligned}$ | $\begin{aligned} & 500 \\ & 450 \end{aligned}$ | $\begin{aligned} & 600 \\ & 650 \end{aligned}$ | $\begin{aligned} & 375 \\ & 300 \end{aligned}$ | $\begin{aligned} & 500 \\ & 450 \end{aligned}$ | $\begin{aligned} & 600 \\ & 675 \end{aligned}$ | $\begin{aligned} & 400 \\ & 300 \end{aligned}$ | $\begin{aligned} & 550 \\ & 500 \end{aligned}$ | $\begin{aligned} & 650 \\ & 750 \end{aligned}$ | ps |
| ${ }_{\text {tsKEW }}$ | Pulse Skew (Note 10) Output-to-Output (Note 11) <br> Part-to-Part (Diff) (Note 11) |  | $\begin{aligned} & 15 \\ & 25 \\ & 50 \end{aligned}$ | $\begin{aligned} & \hline 75 \\ & 95 \\ & 125 \end{aligned}$ |  | $\begin{aligned} & 15 \\ & 30 \\ & 50 \end{aligned}$ | $\begin{array}{\|c\|} \hline 75 \\ 105 \\ 125 \end{array}$ |  | $\begin{aligned} & 15 \\ & 30 \\ & 70 \end{aligned}$ | $\begin{gathered} \hline 80 \\ 105 \\ 150 \end{gathered}$ | ps |
| $\mathrm{t}_{\text {JITTER }}$ | RMS Random Clock Jitter (Note 12) $\quad \mathrm{f}_{\text {in }}=2.0 \mathrm{GHz}$ Peak-to-Peak Data Dependant Jitter $\mathrm{f}_{\text {in }}=2.0 \mathrm{~Gb} / \mathrm{s}$ (Note 13) |  | $\begin{aligned} & 0.5 \\ & 20 \end{aligned}$ | 2.0 |  | $\begin{aligned} & 0.5 \\ & 20 \end{aligned}$ | 2.0 |  | $\begin{aligned} & 0.5 \\ & 20 \end{aligned}$ | 2.0 | ps |
| $\mathrm{V}_{\text {INPP }}$ | Input Voltage Swing (Differential Configuration) (Note 14) | 200 | 800 | 1200 | 200 | 800 | 1200 | 200 | 800 | 1200 | mV |
| $\mathrm{t}_{\mathrm{r}}, \mathrm{t}_{\mathrm{f}}$ | $\begin{aligned} & \hline \text { Output Rise/Fall Times @ } 50 \mathrm{MHz} \\ & (20 \%-80 \%) \end{aligned} \quad \text { Q, } \overline{\mathrm{Q}}$ | 75 | 150 | 250 | 75 | 150 | 250 | 75 | 150 | 275 | ps |

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm . Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.
9. Measured using a 750 mV source, $50 \%$ duty cycle clock source. All loading with $50 \Omega$ to GND - 2.0 V . Input edge rates 150 ps ( $20 \%-80 \%$ ). 10. Pulse Skew $=\left|t_{\text {PLH }}-t_{\text {PHL }}\right|$
11. Skews are valid across specified voltage range, part-to-part skew is for a given temperature.
12. RMS Jitter with 50\% Duty Cycle Input Clock Signal.
13. Peak-to-Peak Jitter with input NRZ PRBS $2^{31-1}$ at $2.0 \mathrm{~Gb} / \mathrm{s}$.
14. Input voltage swing is a single-ended measurement operating in differential mode. The device has a DC gain of $\approx \$ 0$.


Figure 4. Output Voltage Amplitude (Voutpp) / RMS Jitter vs. Input Frequency ( $\mathrm{f}_{\mathrm{in}}$ ) at Ambient Temperature (Typical)


Figure 5. AC Reference Measurement

## Application Information

All NB100LVEP91 inputs can accept LVPECL, LVTTL, LVCMOS, HSTL, CML, or LVDS signal levels. The limitations for differential input signal (LVDS, HSTL, LVPECL, or CML) are the minimum input swing of 150 mV


Figure 6. Standard LVPECL Interface


Figure 8. Standard HSTL Interface


Figure 10. Standard LVTTL Interface
and the maximum input swing of 3.0 V . Within these conditions, the input voltage can range from $\mathrm{V}_{\mathrm{CC}}$ to GND. Examples interfaces are illustrated below in a $50 \Omega$ environment ( $\mathrm{Z}=50 \Omega$ )


Figure 7. Standard LVDS Interface


Figure 9. Standard $\mathbf{5 0 \Omega}$ Load CML Interface


Figure 11. Standard LVCMOS Interface
( D will default to $\mathrm{V}_{\mathrm{Cc}} / 2$ when left open.
A reference voltage of $\mathrm{V}_{\mathrm{cc}} / 2$ should be applied to $D$ input, if $\bar{D}$ is interfaced to CMOS signals.)

ORDERING INFORMATION

| Device | Package | Shipping ${ }^{\dagger}$ |
| :--- | :---: | :---: |
| NB100LVEP91DW | SO-20 | 38 Units / Rail |
| NB100LVEP91DWG | SO-20 <br> $($ Pb-Free $)$ | 38 Units / Rail |
| NB100LVEP91DWR2 | SO-20 | $1000 /$ Tape \& Reel |
| NB100LVEP91DWR2G | SO-20 <br> (Pb-Free) | $1000 /$ Tape \& Reel |
| NB100LVEP91MN | QFN-24 | 92 Units / Rail |
| NB100LVEP91MNG | QFN-24 <br> (Pb-Free) | 92 Units / Rail |
| NB100LVEP91MNR2 | QFN-24 | $3000 /$ Tape \& Reel |
| NB100LVEP91MNR2G | QFN-24 <br> (Pb-Free) | 3000 / Tape \& Reel |

$\dagger$ For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.


Figure 12. Typical Termination for Output Driver and Device Evaluation (See Application Note AND8020/D - Termination of ECL Logic Devices.)

Resource Reference of Application Notes
AN1405/D - ECL Clock Distribution Techniques
AN1406/D - Designing with PECL (ECL at +5.0 V)
AN1503/D - ECLinPS $^{\text {m }}$ I/O SPiCE Modeling Kit
AN1504/D - Metastability and the ECLinPS Family $^{\text {AN1568/D }}-$ Interfacing Between LVDS and ECL
AN1672/D - The ECL Translator Guide
AND8001/D - Odd Number Counters Design
AND8002/D - Marking and Date Codes
AND8020/D - Termination of ECL Logic Devices
AND8066/D - Interfacing with ECLinPS
AND8090/D - AC Characteristics of ECL Devices

## NB100LVEP91

## PACKAGE DIMENSIONS

SO-20 WB
CASE 751D-05
ISSUE G


NOTES:

1. DIMENSIONS ARE IN MILLIMETERS.
2. INTERPRET DIMENSIONS AND TOLERANCES

PER ASME Y14.5M, 1994.
DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSION.
4. MAXIMUM MOLD PROTRUSION 0.15 PER SIDE.
5. DIMENSION B DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION
SHALL BE 0.13 TOTAL IN EXCESS OF B
DIMENSION AT MAXIMUM MATERIAL CONDITION.

| DIM | MILLIMETERS |  |
| :---: | :---: | :---: |
|  | MIN | MAX |
| A | 2.35 | 2.65 |
| A1 | 0.10 | 0.25 |
| B | 0.35 | 0.49 |
| C | 0.23 | 0.32 |
| D | 12.65 | 12.95 |
| E | 7.40 | 7.60 |
| $\mathbf{e}$ | 1.27 BSC |  |
| H | 10.05 | 10.55 |
| $\mathbf{h}$ | 0.25 | 0.75 |
| $\mathbf{L}$ | 0.50 | 0.90 |
| $\boldsymbol{\theta}$ | $0^{\circ}$ | $7^{\circ}$ |

## NB100LVEP91

## PACKAGE DIMENSIONS

QFN 24
MN SUFFIX
24 PIN QFN, $4 \times 4$
CASE 485L-01
ISSUE O


NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.25 AND 0.30 MM FROM TERMINAL.
4. COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.

|  | MILLIMETERS |  |
| :---: | :---: | :---: |
| DIM | MIN | MAX |
| A | 0.80 | 1.00 |
| A1 | 0.00 | 0.05 |
| A2 | 0.60 | 0.80 |
| A3 | 0.20 REF |  |
| b | 0.23 |  |
| D | 0.28 |  |
| D2 | 2.00 |  |
| BSC | 2.90 |  |
| E | 4.00 BSC |  |
| E2 | 2.70 | 2.90 |
| e | 0.50 BSC |  |
| L | 0.35 | 0.45 |

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